

LCFI Testing and Electronics

Andrei Nomerotski (U.Oxford)

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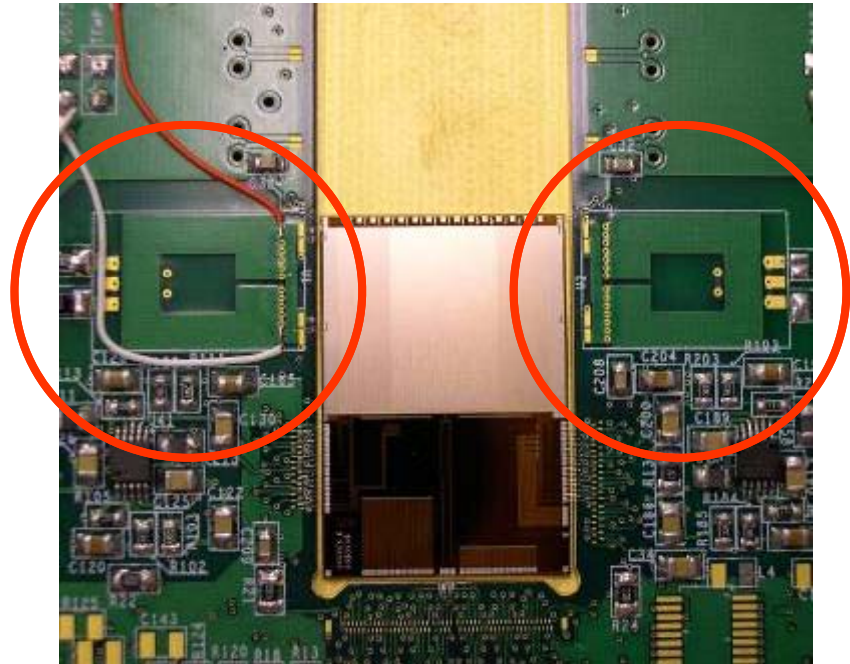
- Clock drive
- External electronics and DAQ
- Radiation damage studies
- Ladder design

Driving Clock

- CPCCD have considerable capacitance and need to run at 50 MHz
- Translates to 20 A clock current to drive 40 nF to 2 V – **this is a major challenge for CPCCD**
 - 1 mm of bond wire = 1 nH = 0.3 Ohm @ 50 MHz → need bump bonding
- Two approaches
 - Transformer Drive
 - **Custom ASIC**, commercial chips not adequate

Transformers as Clock Drive

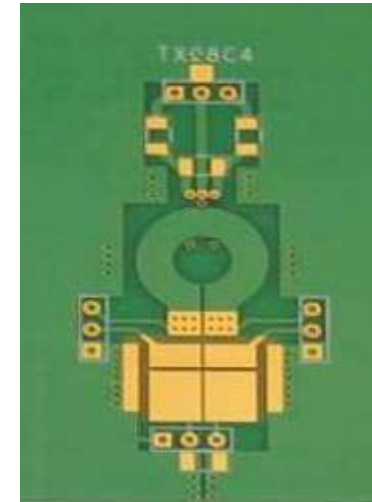
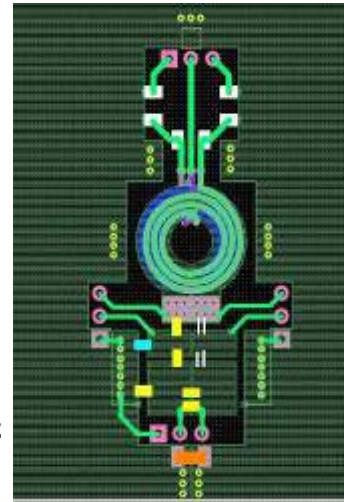
- Planar air core transformer:
 - High voltage/Low current → Low voltage/High current
- Design of 16:1 transformer ratio in 10 layer PCB
 - Can be driven by commercial RF amplifier through 50 Ohm cable
 - Low cost
- Produced and tested in 2006
 - See X-ray hits at 45 MHz
 - Limitations from imbalance between phases and noisy RF generator



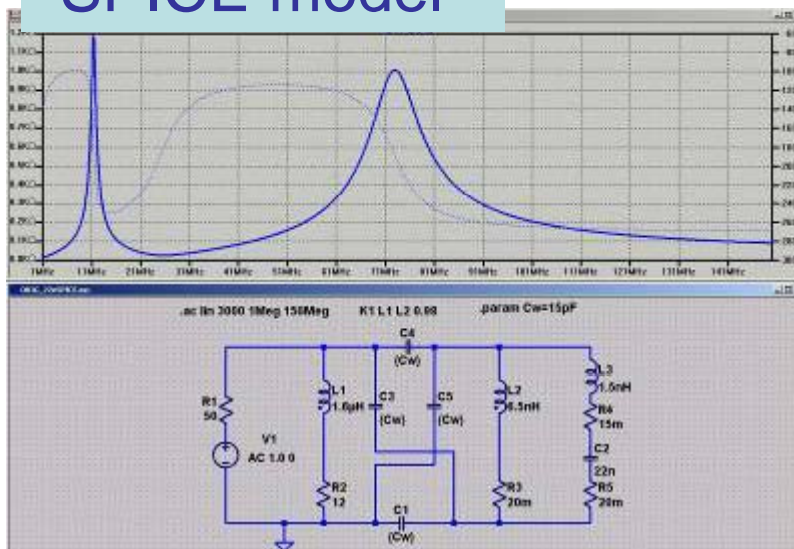
MB4.3 with transformer drive

New Transformers

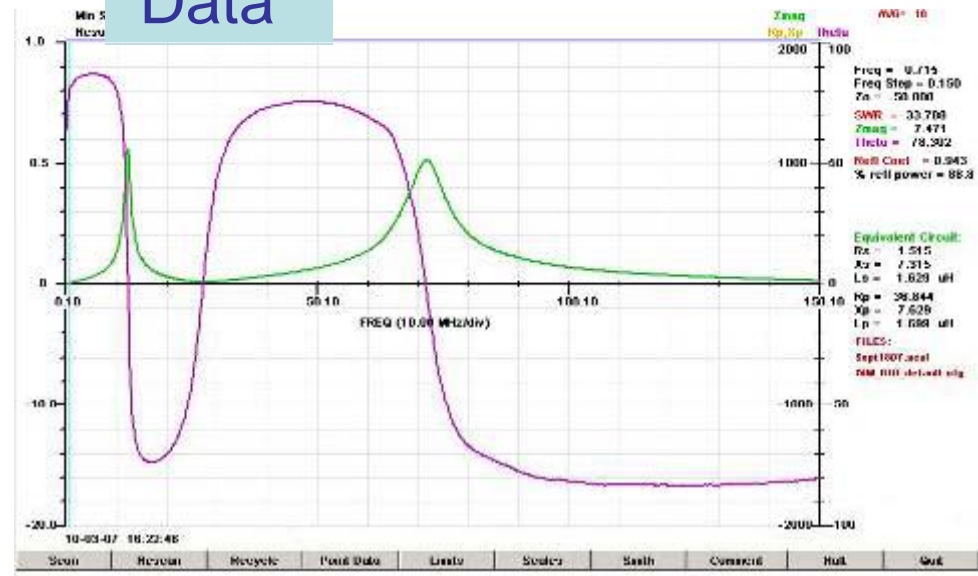
- Phase imbalance caused by parasitics
 - Can be removed by capacitance in series
- New, improved design prepared
 - Different turns ratios and loading schemes
 - Circular spiral winding
- Testing of standalone transformers started
 - Good agreement with simulations: frequency scans
- Transformers are backup after success of CPD1



SPICE model

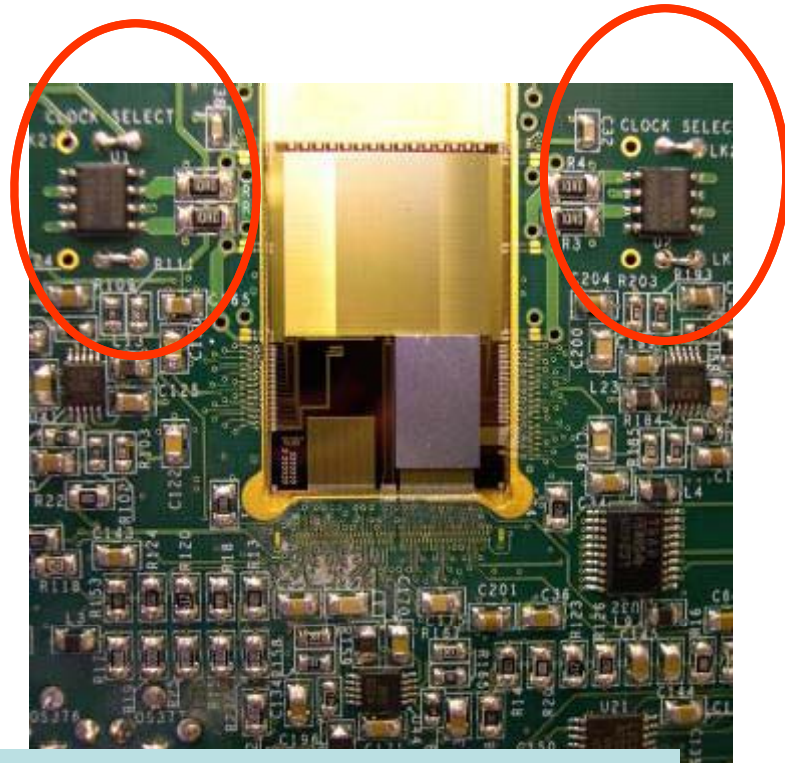


Data



Commercial Clock Drive

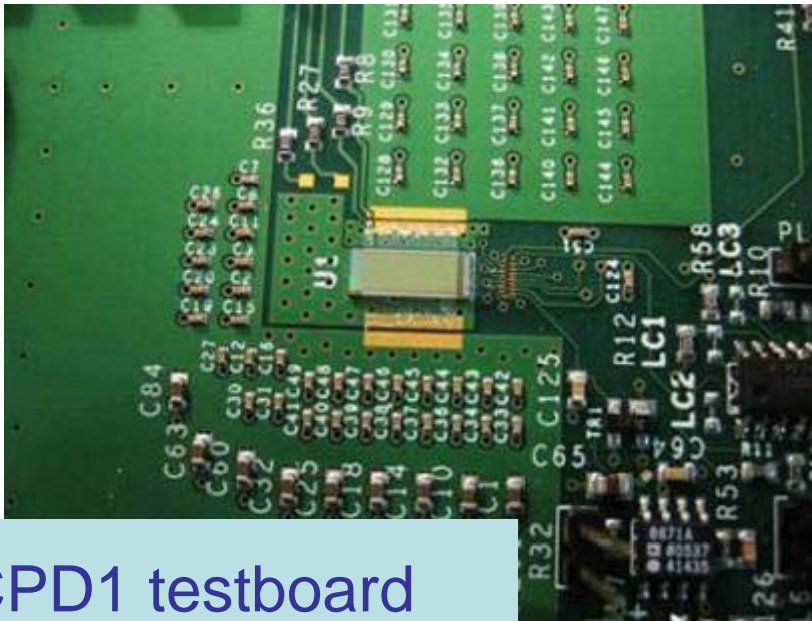
- Initial testing performed using MAX5057 commercial chip
- Used for small CPC2
- Limited to 5 MHz
 - Max current 8 Amp



MB4.4 with MAX5057

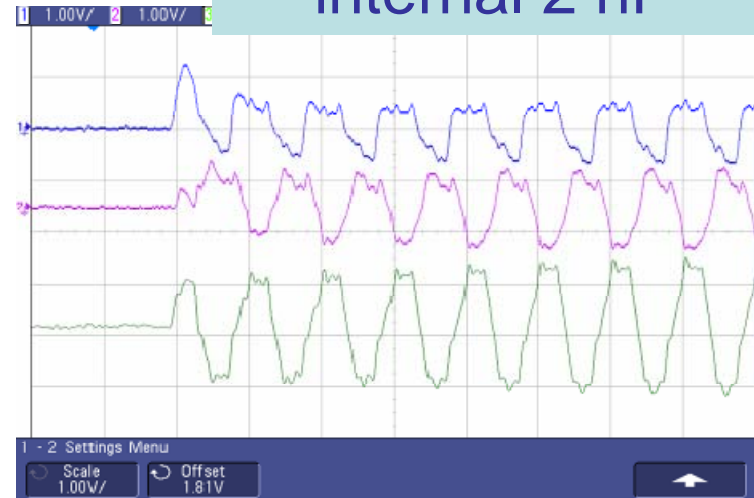
Clock Drive with CPD1

- CPD1 testboard: careful layout to cancel inductance
- CPD1 tests at 50 MHz
 - 32 nF-equivalent internal load
 - 40 nF external load
- With bump bonding should be similar to internal load

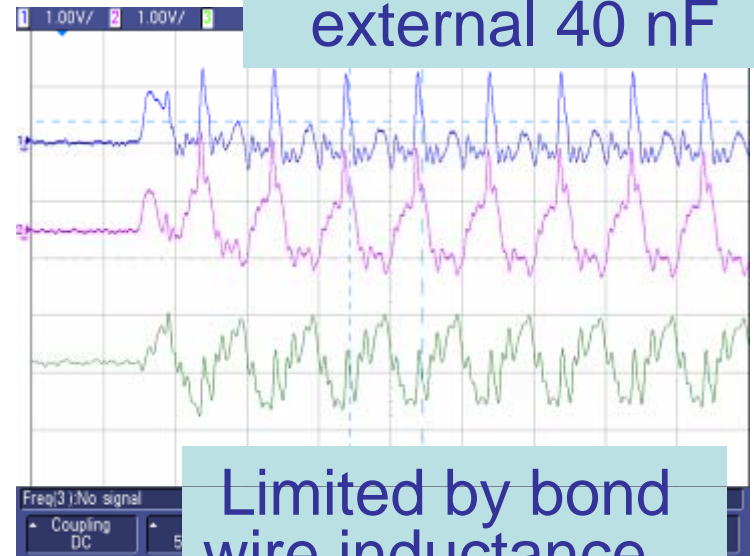


CPD1 testboard

50 MHz, one section
internal 2 nF



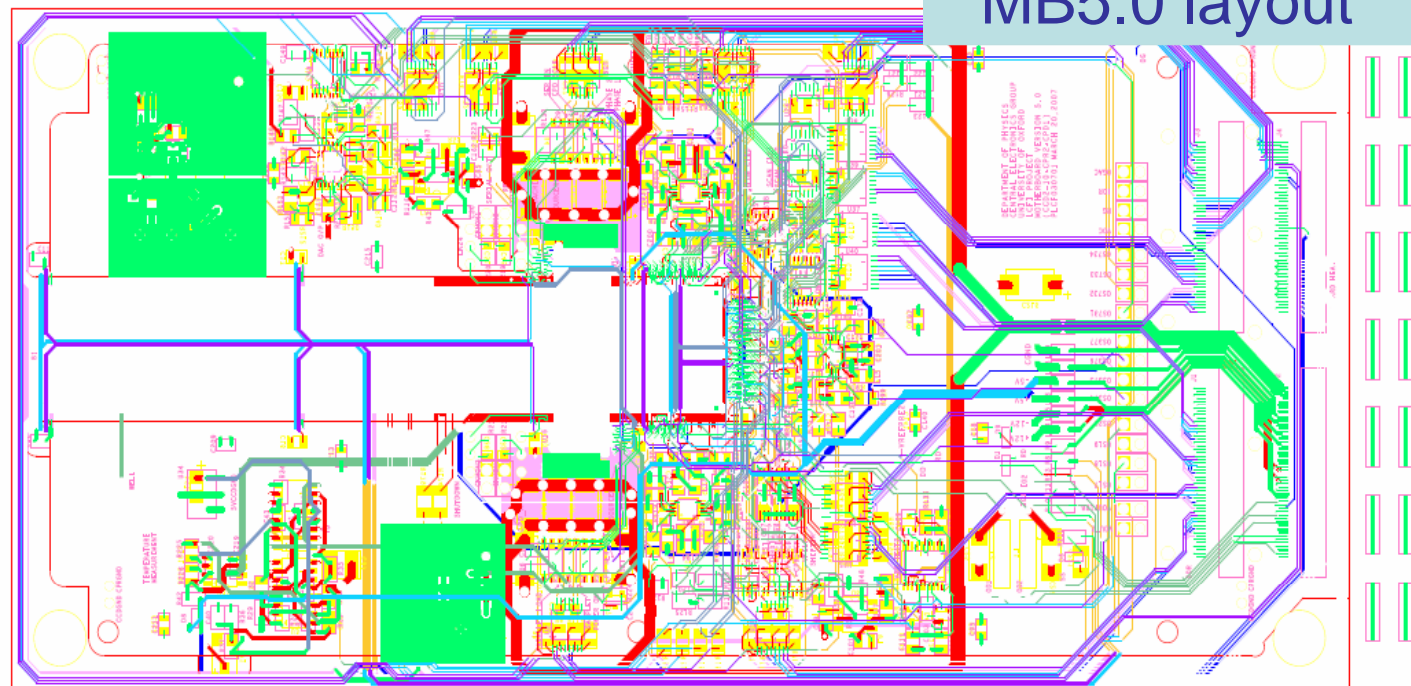
50 MHz, 8 sections
external 40 nF



Limited by bond wire inductance

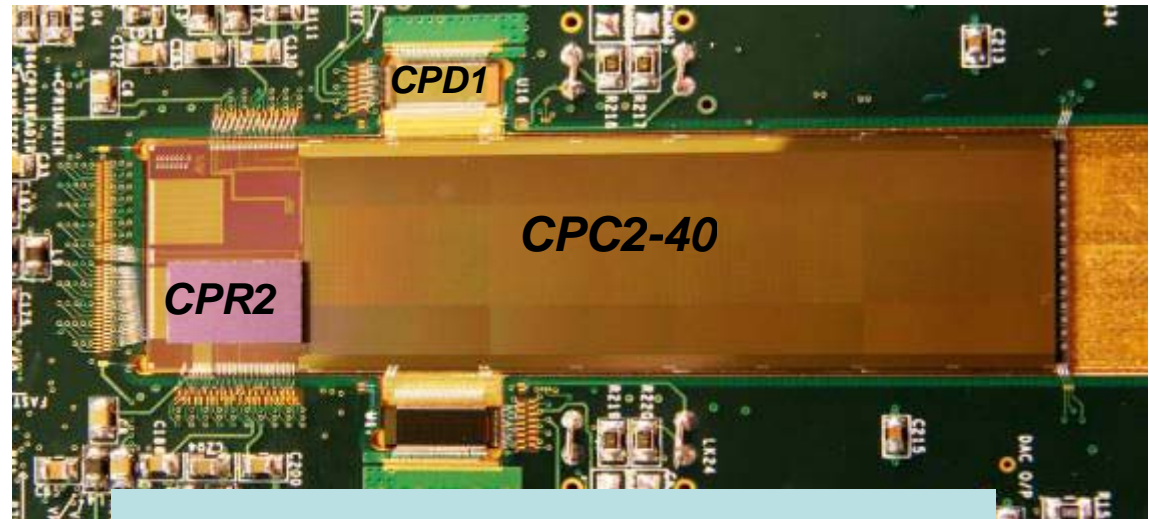
CPC2 MotherBoard

- Interfaces CPC2/CPR2/CPD1 to the outside world, temperature control, monitoring
- Combination of weak analogue, fast digital signals and 20 A clock – challenge!
 - Complicated 14 layer design



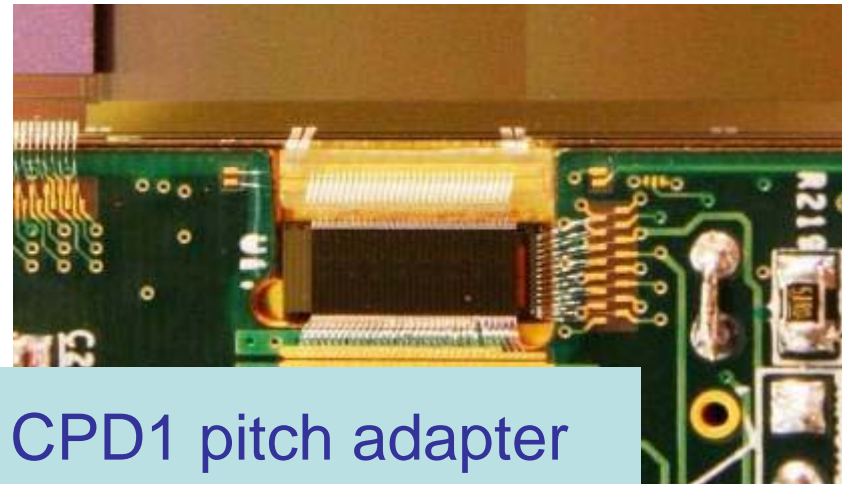
Integration of CPR2/CPR2/CPD1

- Commercial drivers replaced by two custom CPD1 chips
 - Small adapter board to interface CPC2 and CPD1 clock bonding pads



MB5.0 with CPC2/CPR2/CPD1

- Low noise (100 e) performance at 20 MHz



CPC2 – CPD1 pitch adapter

Test Boards

- CPR2 testboard
- ISIS testboard
 - Used for 2007 beam tests
- CPC-T testboard
 - CPC-T are mini-CPCCD with reduced capacitance
 - 50 MHz clock for 4 phase CCD
 - Built-in capacitance measurement



CPR2 testboard



ISIS1 testboard



CPC-T test board with transition board

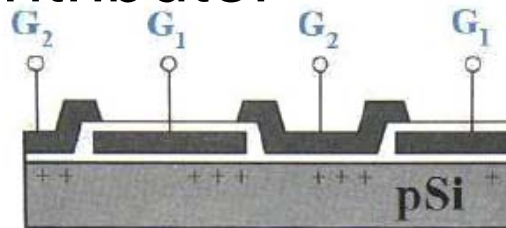
DAQ

- Work horse BVM2 – a VME based module
 - Used in multiple stands in different configurations
- Used to provide all CCD timing sequences and to control all motherboards and testboards
 - Specialized daughter boards
 - SCSI LVDS and TTL configurable outputs
- Successfully used in the ISIS beam tests in October 2007
- New, improved version BVM3 under development
 - Software implementation of many hardwired functions
 - Synchronization between several boards

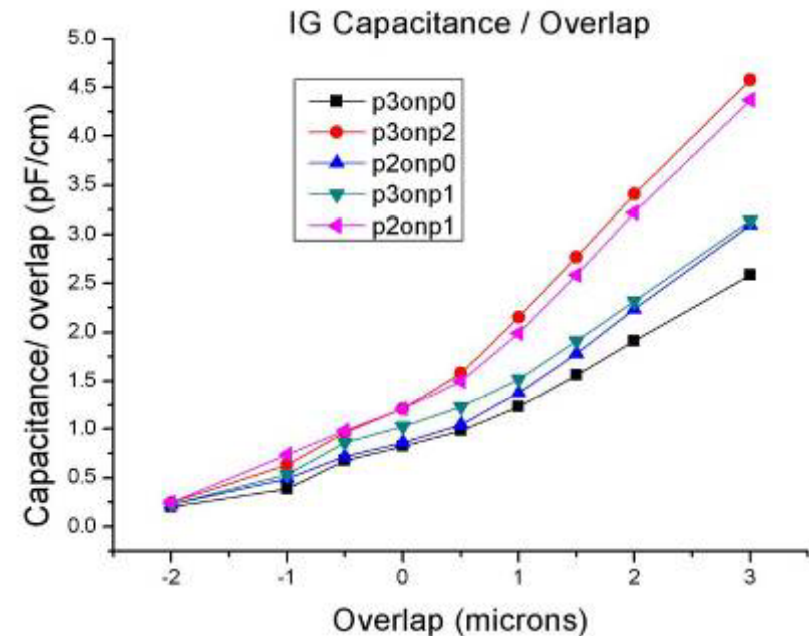
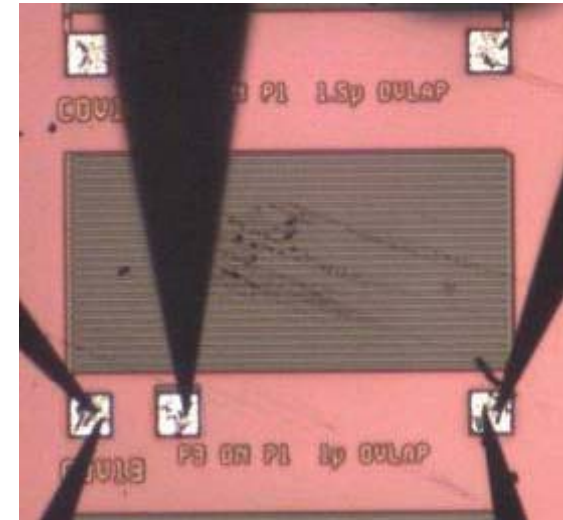


Capacitance Test Structures

- Reduction of CCD capacitance is a major goal
 - Addressed in CPC-T
- Intergate capacitance is the largest contributor

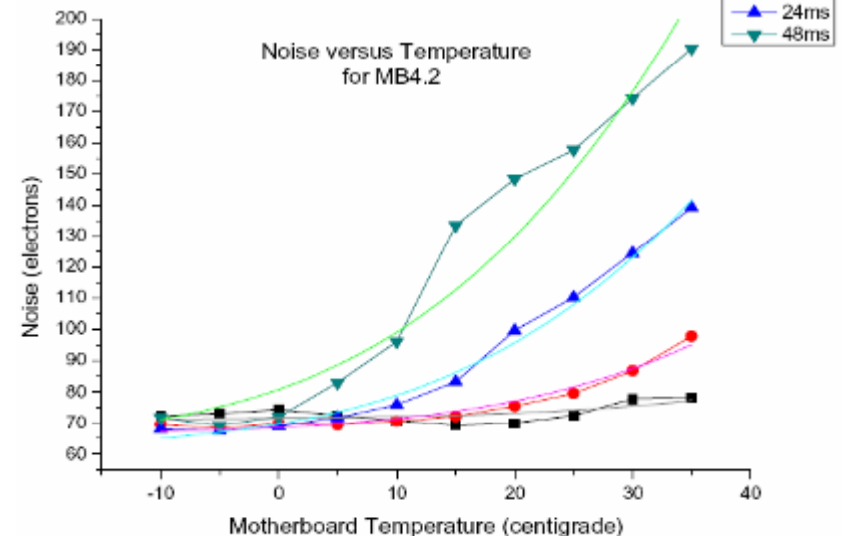
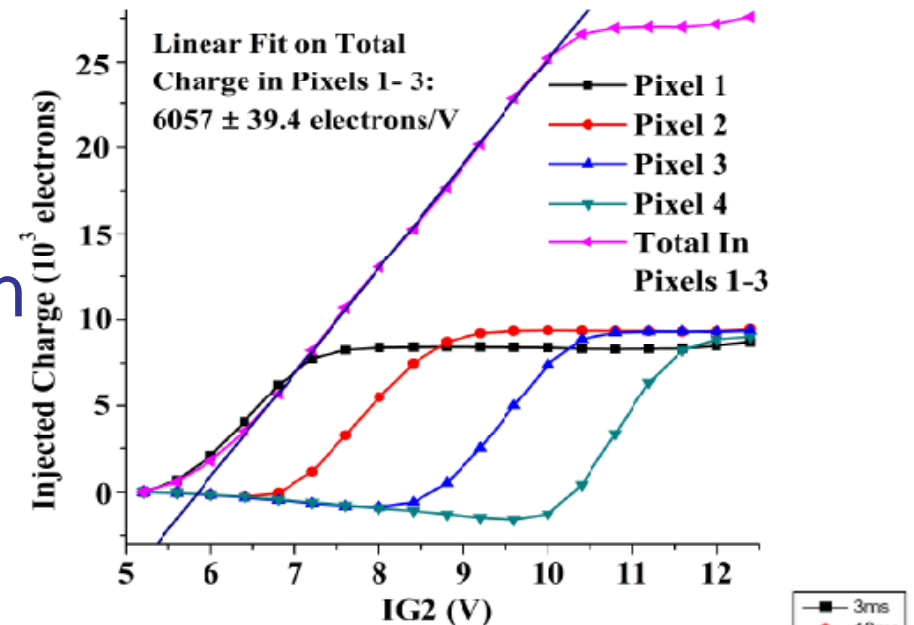


- Tests structures have variable gate overlap [-2 to +3 micron]
 - Good understanding of results
 - Allowed comparison with simulations



CPC2 Well Capacity and Shot Noise

- Well capacity 6000 electrons
 - Used test charge injection
 - Corresponds to ~4 MIPs
- Shot noise is caused by fluctuations of integrated leakage current
 - Varies with integration time and temperature
 - ~50 fA/pixel at 20°C



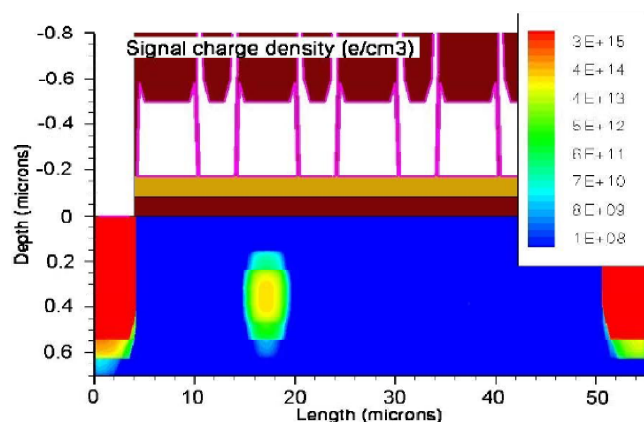
Radiation Damage: What to Expect?

At R=14 mm

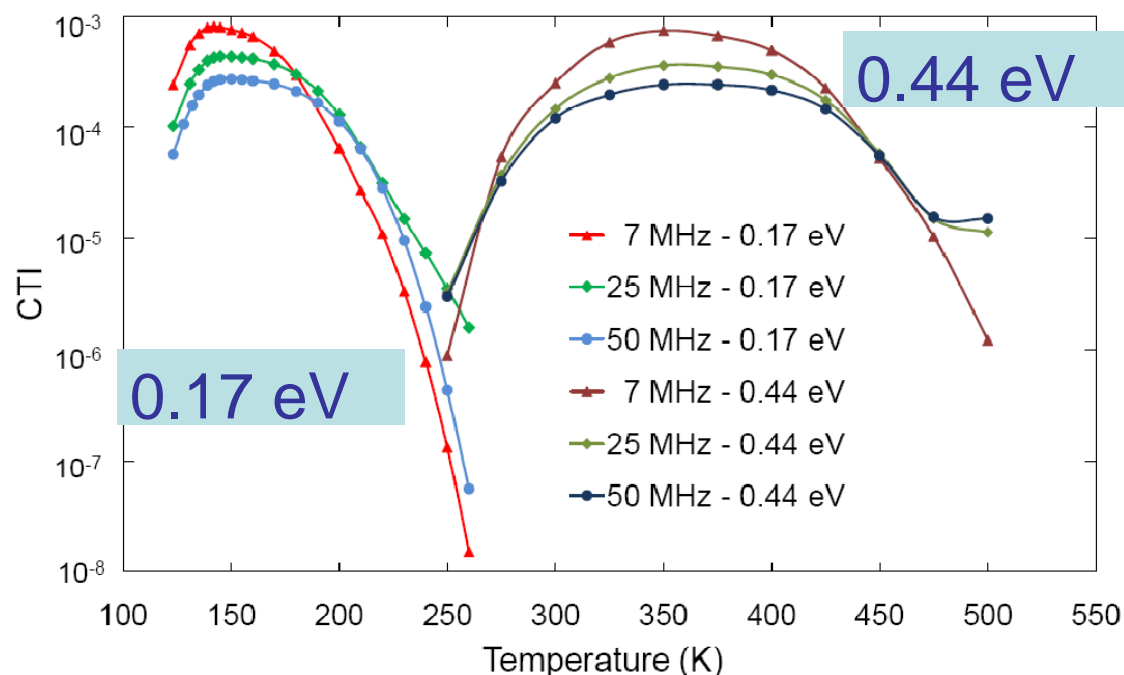
- Pair background from Beamstrahlung
 - 10 MeV electrons, $3.5 \text{ /bx/cm}^2 \rightarrow 0.5 \cdot 10^{12} \text{ /year/cm}^2 (\rightarrow 15 \text{ krad/year})$
 - Surface damage: accumulation of charge at SiO_2/Si interfaces
 - Bulk damage: traps & leakage current
- Neutrons
 - 1 MeV n; $0.01 \text{ /bx/cm}^2 \rightarrow 1.6 \cdot 10^9 \text{ /year/cm}^2$
 - Bulk damage
- Surface damage can be accommodated by adjustment of CCD biases
- Bulk damage translates to trap density
 - 0.17 eV trap; $3 \cdot 10^{11} \text{ /year/cm}^3$; caused by electrons
 - 0.44 eV trap; $4 \cdot 10^{10} \text{ /year/cm}^3$; caused by electrons and neutrons

Radiation Damage: Simulations

- ISE-TCAD simulations of charge propagation in the presence of traps
 - Charge trapped and later released: function of T and frequency
 - There is an optimum temperature window of low Charge Transfer Inefficiency (CTI) between $-50\text{ }^{\circ}\text{C}$ and $0\text{ }^{\circ}\text{C}$
- This should be confirmed experimentally in CPC2 and CPC-T

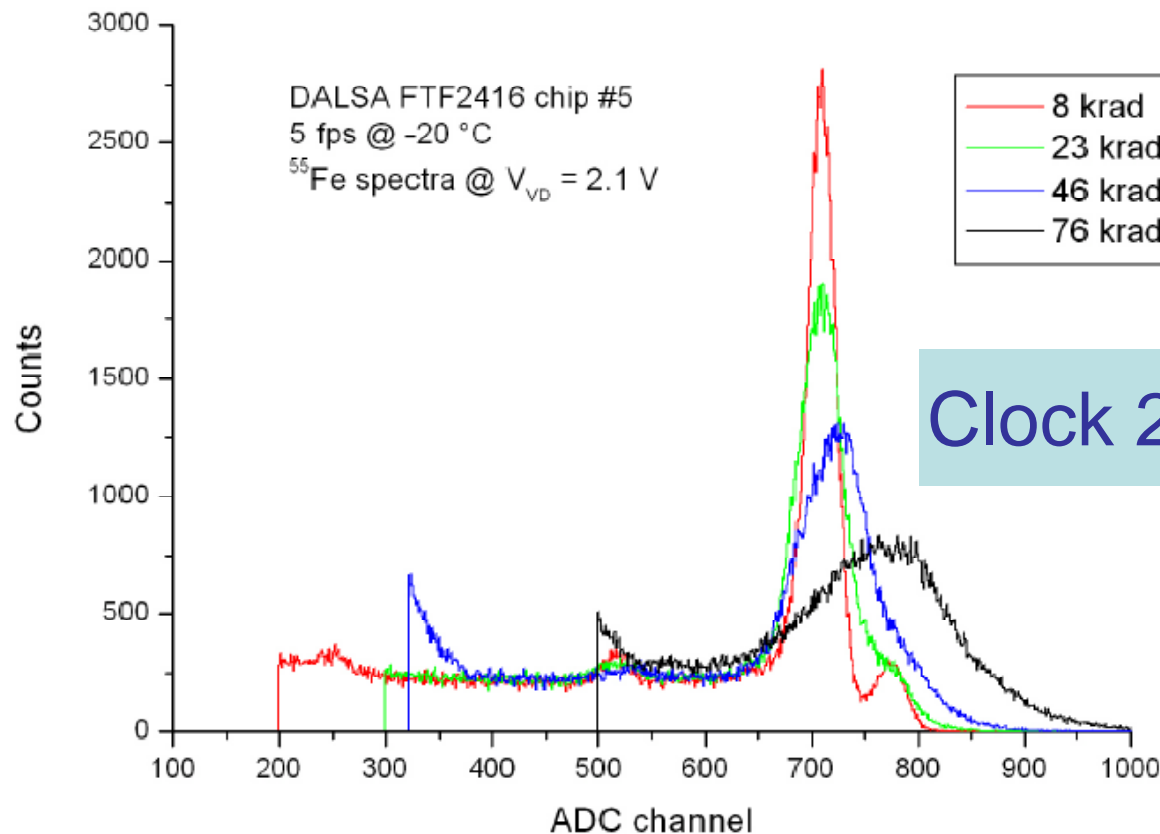


CCD model



Irradiations of DALSA CCDs

- Study to verify rad hardness of non-overlapping polySi gates
 - Charge-up of SiO₂ insulation between gates
 - Relevant for ISIS technologies with small cells
- DALSA CCD survived 70 krad from ⁹⁰Sr beta source
 - No change in minimal clock amplitude

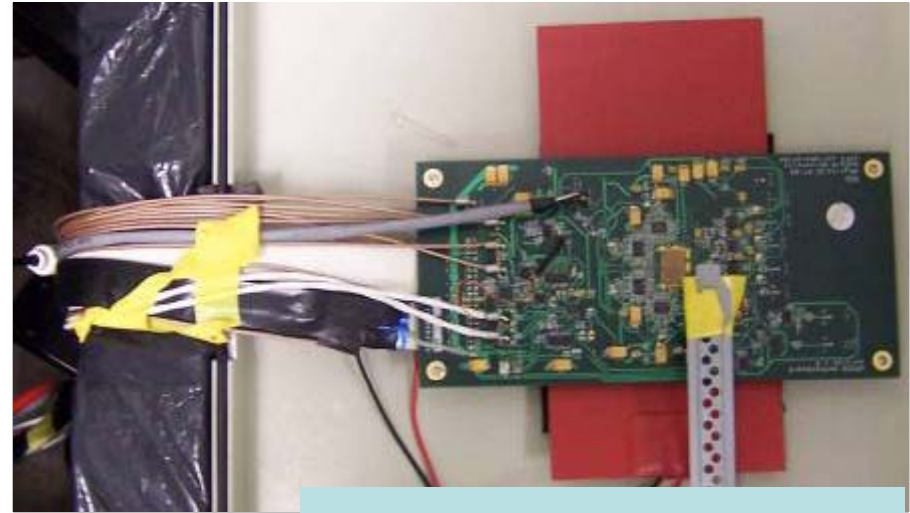


Clock 2.1 V; 5.9 keV ⁵⁵Fe

Irradiations

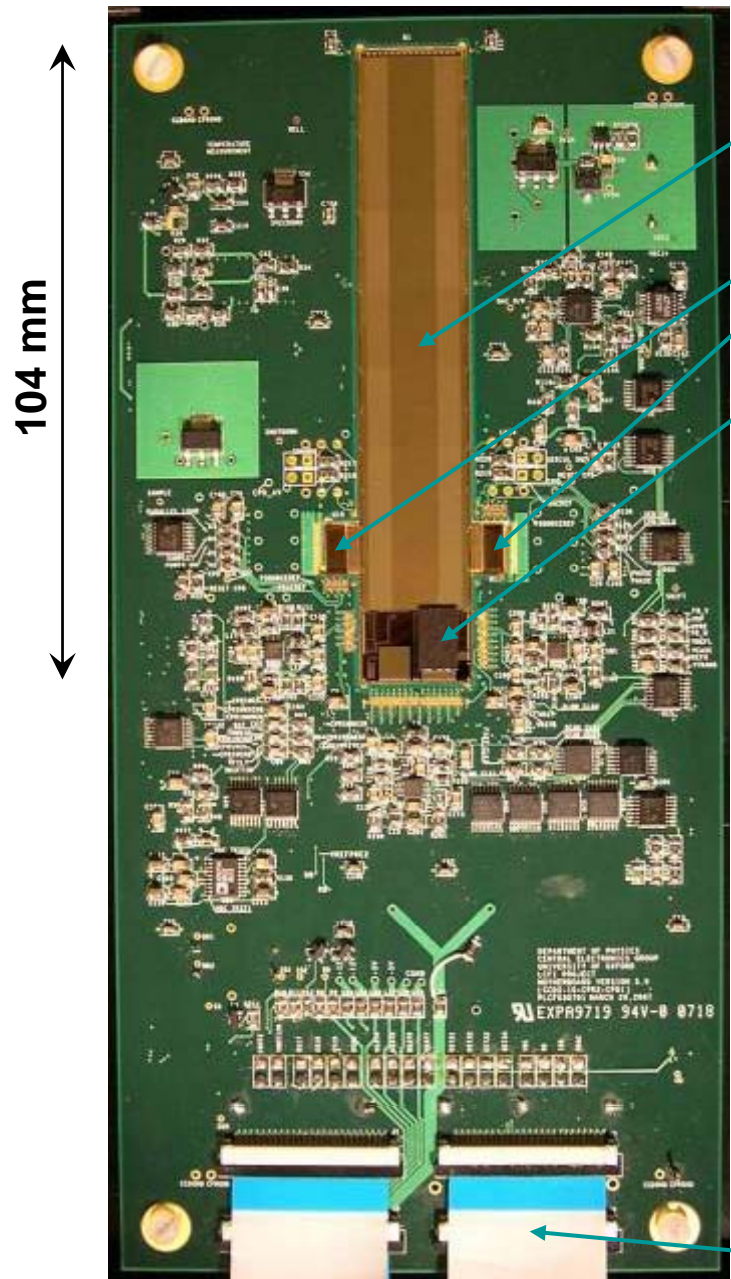
Plan

- Characterize CPC1 before irradiation
 - CTI vs temperature
- Irradiate with sources
 - ^{252}Cf , neutrons ~ 2 MeV
 - ^{90}Sr , electrons ~ 1 MeV
- Measure CTI after irradiation



CPC1 motherboard

Towards Ladder with CPCCD

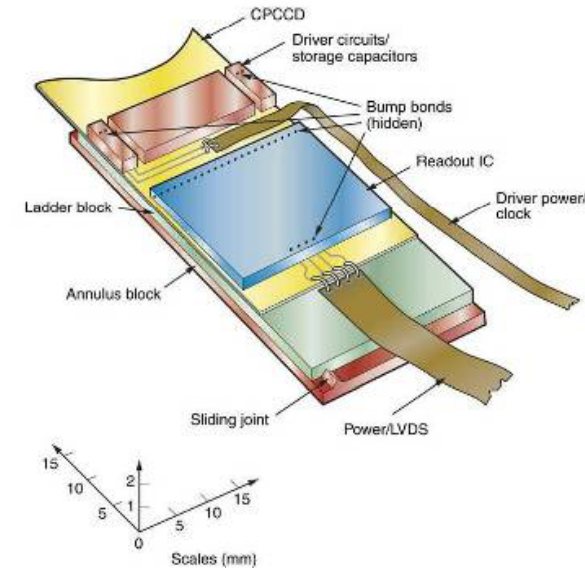


CPC2-70

Two driver chips CPD1

Bump-bonded CPR2

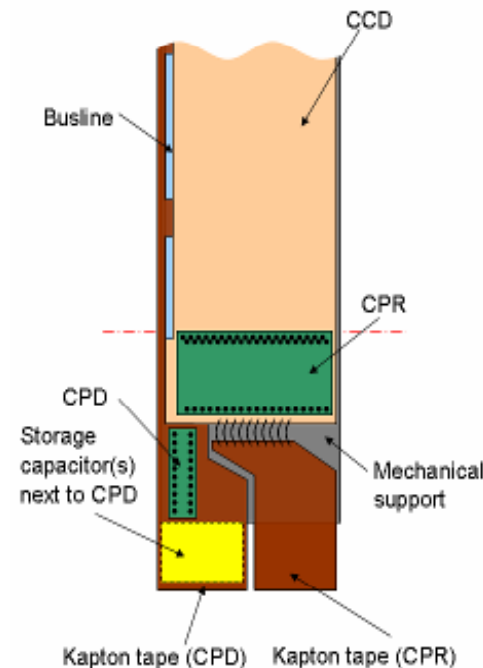
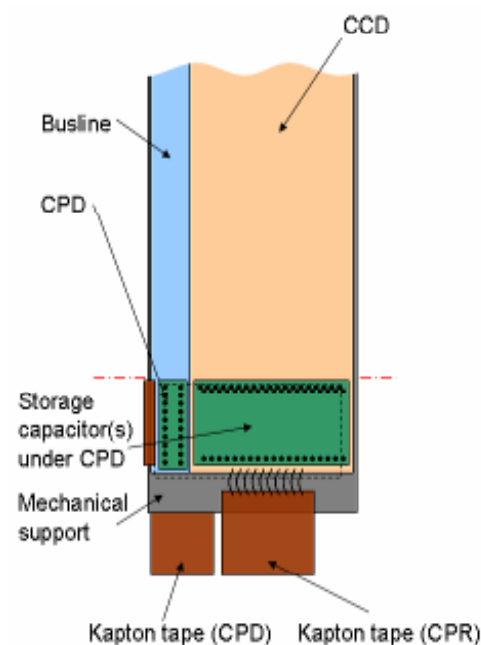
Flexible cables



- We already operate simultaneously all components of Vertex Detector ladder
 - With final sensor length 100 mm
- Next step : first realistic ladder designs

Ladder Design

- Considered different configurations how to connect CPR and CPD to CPCCD
 - Low mass flexible kapton cables to bring power and signals
 - Short barrel design allows to place CPR and CPD on different sides of ladder
- Clock distribution and required clock current play key role
 - Clock distribution using double metal layer (DLM) bus. Minimizes amplitude drops but doubles capacitance – needs optimization.
 - How far away need large capacitors?
- Strong influence on CPC3 design and connections to all aspects of the LCFI programme



Summary

- Strong involvement in algorithms and physics studies
 - State of the art vertexing package released
- Column Parallel CCDs perform well at 20 MHz with custom clock driver CPD1
 - Run at 45 MHz with transformer drive
- CPCCD readout chip CPR2 runs at 7 MHz
 - Improved version CPR2A ready soon
- Have proof of principle for ISIS and actively looking for vendors for next generation ISIS2
- Actively exploring various mechanical solutions based on foams and thin silicon

- Ready to demonstrate a full scale ladder prototype in the next funding cycle